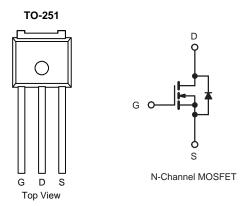


NCE2025I-VB Datasheet N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	$R_{DS(on)}$ ($m\Omega$)	I _D (A)	Q _g (Typ.)	
30	7 at V _{GS} = 10 V	50	19 nC	
	9 at V _{GS} = 4.5 V	45	19110	



FEATURES

- · Halogen-free
- Trench Gen III Power MOSFET
- 100 % R_g Tested
- 100 % UIS Tested

APPLICATIONS

- DC/DC Conversion
 - System Power

Parameter		Symbol	Limit	Unit
Drain-Source Voltage Gate-Source Voltage		V _{DS} V _{GS}	30	V
			± 20	V
	T _C = 25 °C		50	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	I _D	45	
,	T _A = 25 °C	1 [14 ^{b, c}	A
	T _A = 70 °C		10 ^{b, c}	
Pulsed Drain Current		I _{DM}	150	
Avalanche Current	L = 0.1 mH	I _{AS}	25	
Avalanche Energy		E _{AS}	40	mJ
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	15	А
	T _A = 25 °C	-3	2.9 ^{b, c}	
	T _C = 25 °C		28	
Maximum Power Dissipation	$T_C = 70 ^{\circ}C$	P _D	18	w
Maximum Fower Dissipation	T _A = 25 °C] 'D	3.5 ^{b, c}	
	T _A = 70 °C	1	2.2 ^{b, c}	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C
Soldering Recommendations (Peak Tempera	ature)		260	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient	t ≤ 10 s	R _{thJA}	29	36	°C/W	
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	3.6	4.5	0/11	

Notes:

- a. Based on T_C = 25 °C.
 b. Surface Mounted on 1" x 1" FR4 board.
- c. t = 10 s.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit		
Static				•				
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V		
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	In = 250 HA		I _D = 250 μA		33		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5				
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu A$	1.2		3.0	V		
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA		
Zara Cata Valta na Duain Comment		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ		
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			5			
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	15			Α		
Danis Common Co Oloto Donisto and		$V_{GS} = 10 \text{ V}, I_{D} = 10 \text{ A}$		7		mΩ		
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_{D} = 7 \text{ A}$		9				
Forward Transconductance ^a	g _{fs}	V _{DS} = 15 V, I _D = 10 A		24		S		
Dynamic ^b				•				
Input Capacitance	C _{iss}			1700				
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		200		pF		
Reverse Transfer Capacitance	C _{rss}			150				
Tatal Cata Observe	Qg	$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		33		nC		
Total Gate Charge				18				
Gate-Source Charge	Q _{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 10 \text{ A}$		7.3				
Gate-Drain Charge	Q _{gd}			6.2				
Gate Resistance	R_g	f = 1 MHz 0.2		0.8	1.6	Ω		
Turn-On Delay Time	t _{d(on)}			15	30	ns		
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.5 Ω		12	24			
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ 10 A, V_{GEN} = 4.5 V, R_g = 1 Ω		13	26			
Fall Time	t _f			10	20			
Turn-On Delay Time	t _{d(on)}			9	18			
Rise Time	t _r	V_{DD} = 15 V, R_L = 1.5 Ω		9	18			
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 10$ A, $V_{GEN}=10$ V, $R_g=1$ Ω		14	28			
Fall Time	t _f			8	16			
Drain-Source Body Diode Characteristi	cs			•				
Continuous Source-Drain Diode Current	I _S	$T_C = 25 ^{\circ}C$			16	Α		
Pulse Diode Forward Current	I _{SM}				32			
Body Diode Voltage	V_{SD}	$I_S = 3 \text{ A}, V_{GS} = 0 \text{ V}$		0.78	1.2	V		
Body Diode Reverse Recovery Time	t _{rr}			17	34	ns		
Body Diode Reverse Recovery Charge	Q _{rr}	I _F = 10 A, dI/dt = 100 A/μs, T _J = 25 °C		9.5	19	nC		
Reverse Recovery Fall Time	t _a	$i_F = 10 \text{ A}$, $u_1/u_1 = 100 \text{ A/}\mu s$, $i_J = 25 \text{ C}$		10		ns		
Reverse Recovery Rise Time	t _b			7				

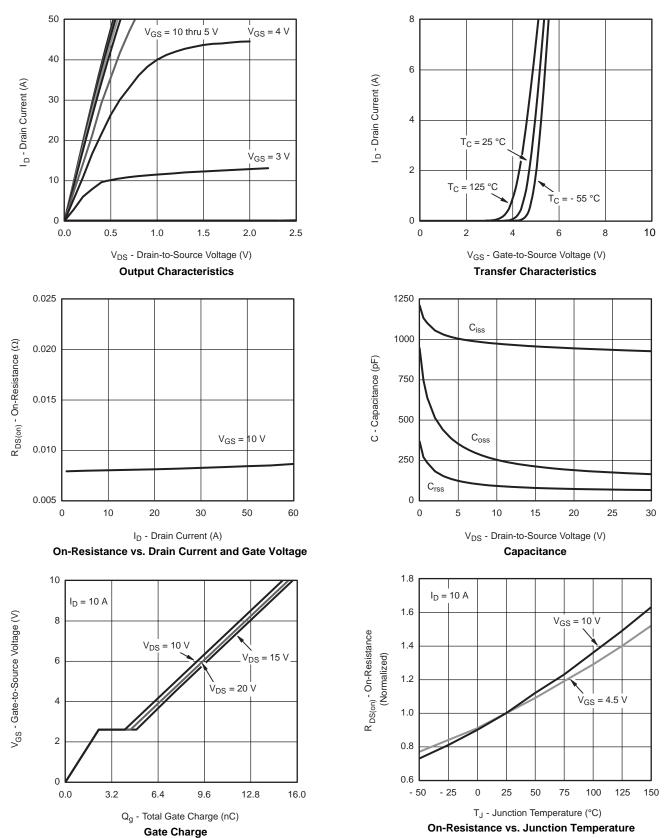
Notes:

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

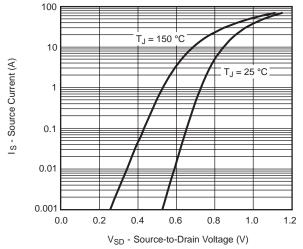
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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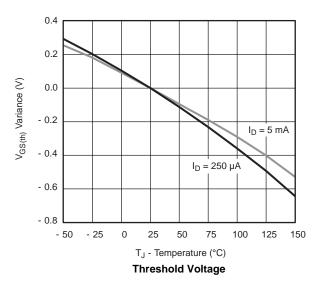








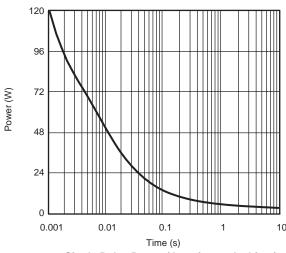
Source-Drain Diode Forward Voltage



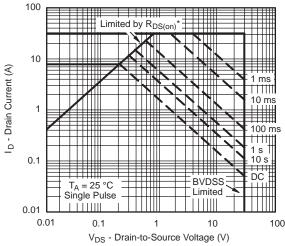
0.06 $I_D = 10^{\circ} A$ 0.05 $R_{DS(on)}$ - On-Resistance (Ω) 0.04 0.03 $T_J = 125$ °C 0.02 0.01 $T_J = 25 \, ^{\circ}C$ 0.00 2 3 0 1 4 5 9

V_{GS} - Gate-to-Source Voltage (V)

On-Resistance vs. Gate-to-Source Voltage



Single Pulse Power (Junction-to-Ambient)

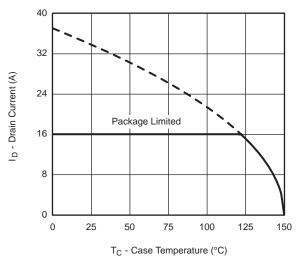


* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

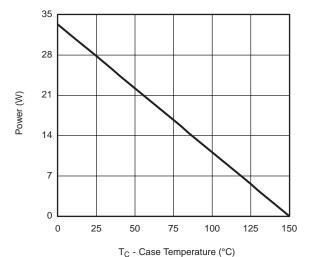
Safe Operating Area, Junction-to-Ambient

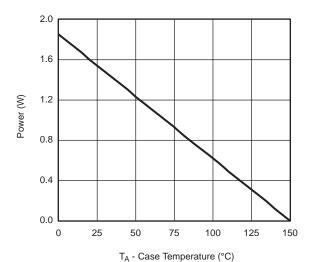
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Current Derating*



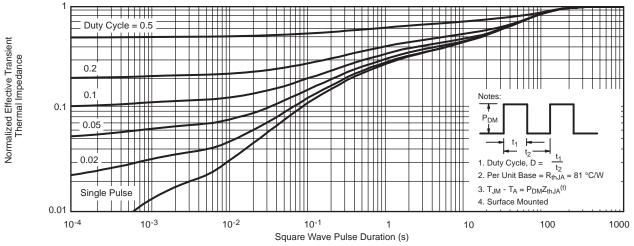


Power, Junction-to-Case

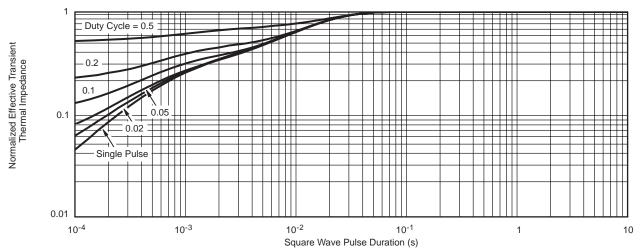
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





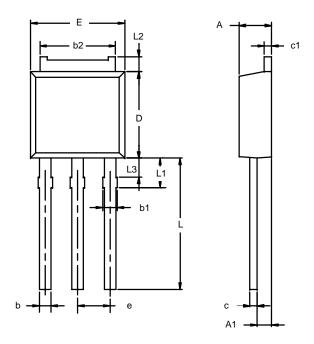
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



TO-251AA (DPAK)



Note:	Dimension	L3 is for	reference only.
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	MILLIM	IETERS	INC	HES	
Dim	Min	Max	Min	Max	
Α	2.21	2.38	0.087	0.094	
A 1	0.89	1.14	0.035	0.045	
b	0.71	0.89	0.028	0.035	
b1	0.76	1.14	0.030	0.045	
b2	5.23	5.43	0.206	0.214	
С	0.46	0.58	0.018	0.023	
с1	0.46	0.58	0.018	0.023	
D	5.97	6.22	0.235	0.245	
Е	6.48	6.73	0.255	0.265	
е	2.28	BSC	0.090 BSC		
L	3.89	9.53	0.153	0.375	
L1	1.91	2.28	0.075	0.090	
L2	0.89	1.27	0.035	0.050	
L3	1.15	1.52	0.045	0.060	
ECN: S-03946—Rev. E, 09-Jul-01 DWG: 5346					



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